



July 2005

# FDFMC2P120

## Integrated P-Channel PowerTrench<sup>®</sup> MOSFET and Schottky Diode

### General Description

FDFMC2P120 combines the exceptional performance of Fairchild's PowerTrench MOSFET technology with a very low forward voltage drop Schottky barrier rectifier in a MicroFET package.

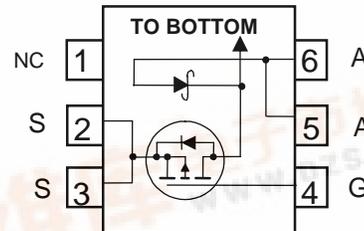
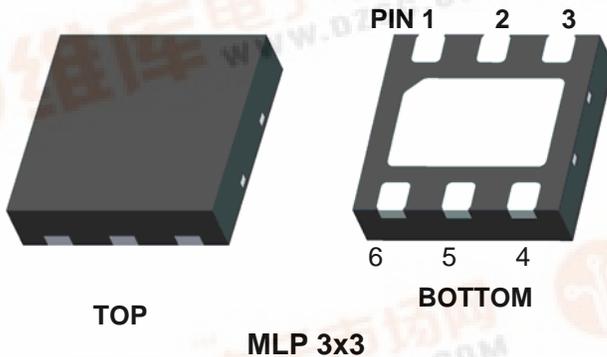
This device is designed specifically as a single package solution for Buck Boost. It features a fast switching, low gate charge MOSFET with very low on-state resistance.

### Applications

- Buck Boost

### Features

- -2 A, -20 V  $R_{DS(ON)} = 125\text{ m}\Omega @ V_{GS} = -4.5\text{ V}$   
 $R_{DS(ON)} = 200\text{ m}\Omega @ V_{GS} = -2.5\text{ V}$
- Low Profile – 0.8mm maximum – in the new package MicroFET 3x3 mm



### Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain-Source Voltage	-20	V
$V_{GSS}$	Gate-Source Voltage	$\pm 12$	V
$I_D$	Drain Current – Continuous (Note 1a)	-3.5	A
		-10	A
$V_{RRM}$	Schottky Repetitive Peak Reverse Voltage	20	V
$I_O$	Schottky Average Forward Current (Note a)	2	A
$P_D$	Power Dissipation (Steady State) (Note 1a) (Note 1b)	2.4	W
		1.2	W
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ\text{C}$

### Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	60	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1b)	145	

### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
2P120	FDFMC2P120	7"	12mm	3000 units



## Electrical Characteristics

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain–Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = -250\ \mu\text{A}$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		-11		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -16\text{ V}, V_{GS} = 0\text{ V}$			-1	$\mu\text{A}$
$I_{GSS}$	Gate–Body Leakage,	$V_{GS} = \pm 12\text{ V}, V_{DS} = 0\text{ V}$			$\pm 100$	nA
<b>On Characteristics (Note 2)</b>						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_G, I_D = -250\ \mu\text{A}$	-0.6	-1.0	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		3		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain–Source On–Resistance	$V_{GS} = -4.5\text{ V}, I_D = -2\text{ A}$ $V_{GS} = -2.5\text{ V}, I_D = -2\text{ A}$ $V_{GS} = -4.5\text{ V}, I_D = -2\text{ A}, T_J = 125^\circ\text{C}$		101 145 136	125 200 180	m $\Omega$
$I_{D(on)}$	On–State Drain Current	$V_{GS} = -2.5\text{ V}, V_{DS} = -5\text{ V}$	-10			A
$g_{FS}$	Forward Transconductance	$V_{DS} = -5\text{ V}, I_D = -3.5\text{ A}$		6		S
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$		280		pF
$C_{oss}$	Output Capacitance			65		pF
$C_{rss}$	Reverse Transfer Capacitance			35		pF
$R_G$	Gate Resistance	$V_{GS} = 0\text{ V}, f = 1.0\text{ MHz}$		7		$\Omega$
<b>Switching Characteristics (Note 2)</b>						
$t_{d(on)}$	Turn–On Delay Time	$V_{DD} = -10\text{ V}, I_D = -1\text{ A},$ $V_{GS} = -4.5\text{ V}, R_{GEN} = 6\ \Omega$		8	16	ns
$t_r$	Turn–On Rise Time			12	22	ns
$t_{d(off)}$	Turn–Off Delay Time			11	20	ns
$t_f$	Turn–Off Fall Time			3.2	6.4	ns
$Q_g$	Total Gate Charge	$V_{DS} = -10\text{ V}, I_D = -3.5\text{ A},$ $V_{GS} = -4.5\text{ V}$		3	4	nC
$Q_{gs}$	Gate–Source Charge			0.7		nC
$Q_{gd}$	Gate–Drain Charge			1		nC
<b>Drain–Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain–Source Diode Forward Current				-2	A
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = -2\text{ A}$ (Note 2)		-0.9	-1.2	V
$t_{rr}$	Diode Reverse Recovery Time	$I_F = -3.5\text{ A},$ $di_F/dt = 100\text{ A}/\mu\text{s}$		13		nS
$Q_{rr}$	Diode Reverse Recovery Charge			3		nC

**Notes:**

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  are guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design.

- (a).  $R_{\theta JA} = 60^\circ\text{C}/\text{W}$  when mounted on a  $1\text{ in}^2$  pad of 2 oz copper
- (b).  $R_{\theta JA} = 145^\circ\text{C}/\text{W}$  when mounted on a minimum pad of 2 oz copper

2. Pulse Test: Pulse Width < 300 $\mu\text{s}$ , Duty Cycle < 2.0%

**Electrical Characteristics**

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Schottky Diode Characteristic</b>						
$V_R$	Reverse Voltage	$I_R = 1\text{mA}$	20			V
$I_R$	Reverse Leakage	$V_R = 5\text{V}$	$T_J = 25^\circ\text{C}$		100	$\mu\text{A}$
			$T_J = 100^\circ\text{C}$		10	mA
$V_F$	Forward Voltage	$I_F = 1\text{A}$		0.32	0.39	V

## Typical Characteristics

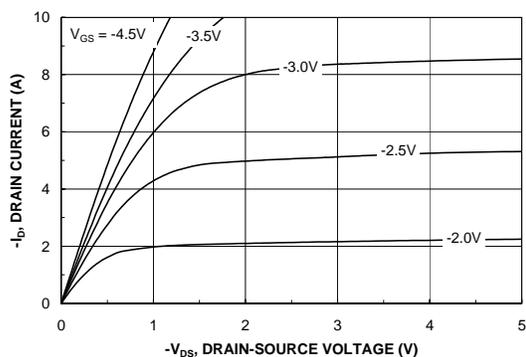


Figure 1. On-Region Characteristics.

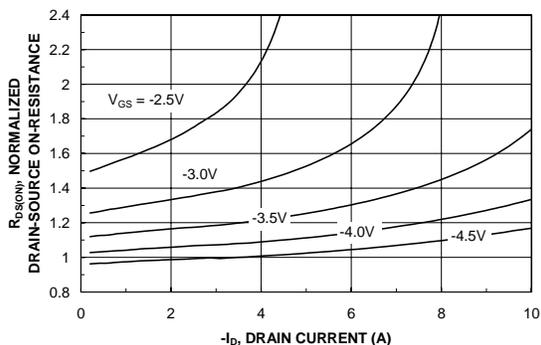


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

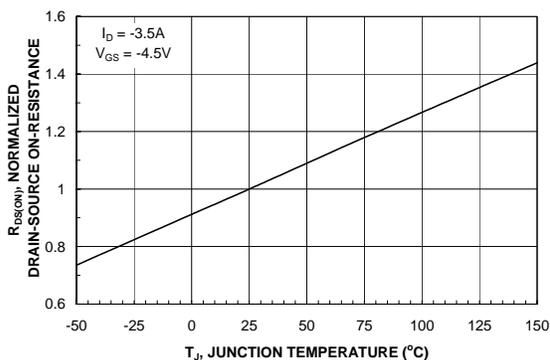


Figure 3. On-Resistance Variation with Temperature.

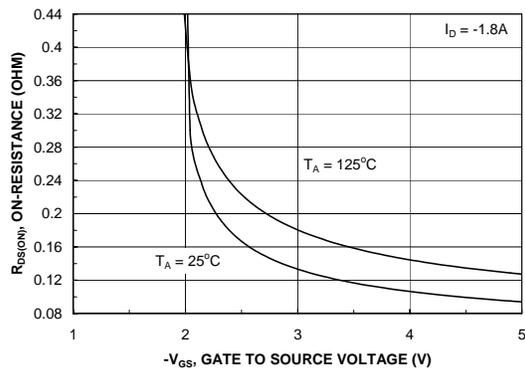


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

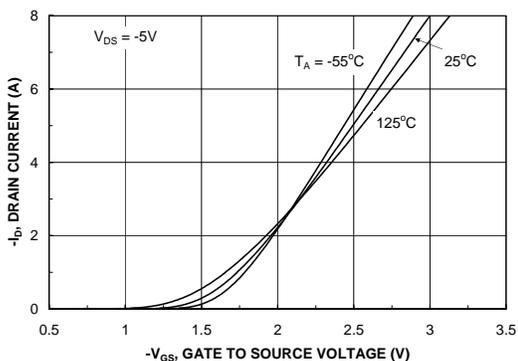


Figure 5. Transfer Characteristics.

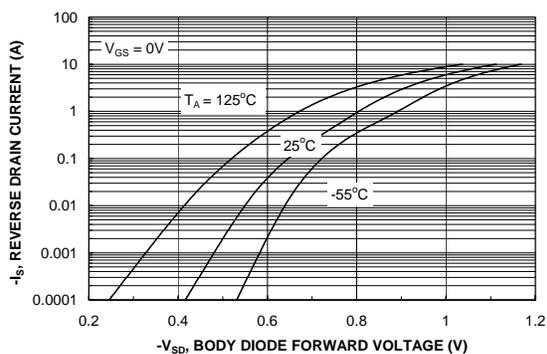
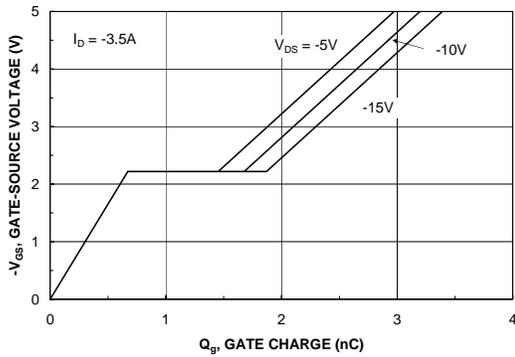
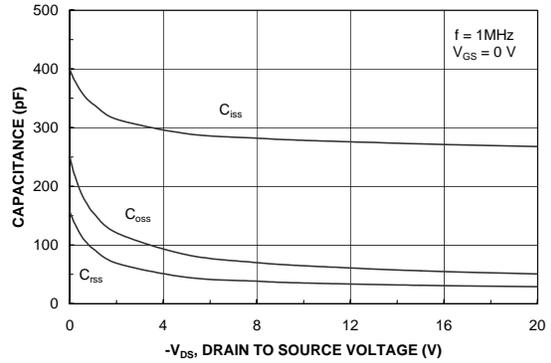


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

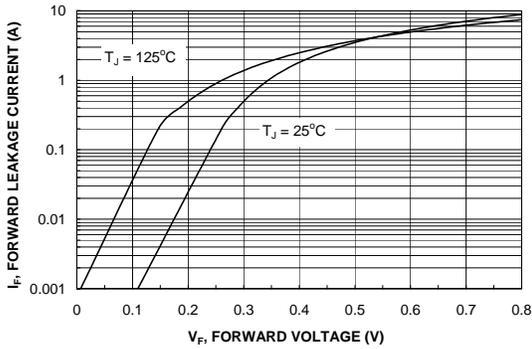
## Typical Characteristics



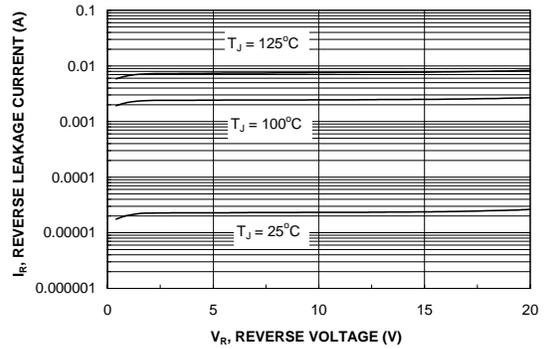
**Figure 7. Gate Charge Characteristics.**



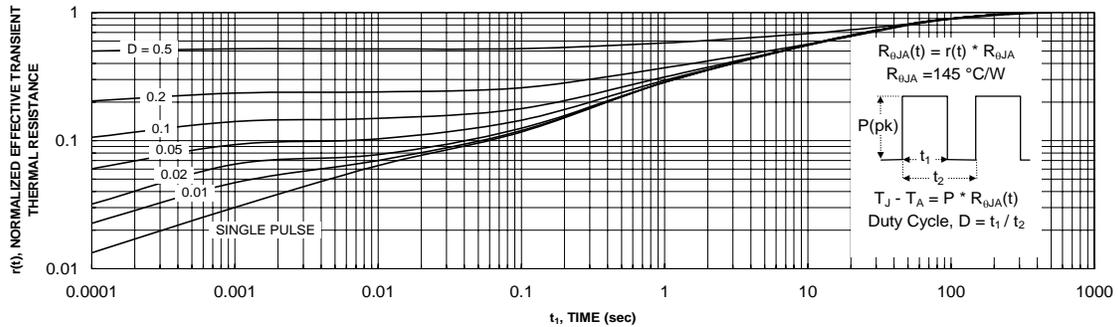
**Figure 8. Capacitance Characteristics.**



**Figure 9. Schottky Diode Forward Voltage.**

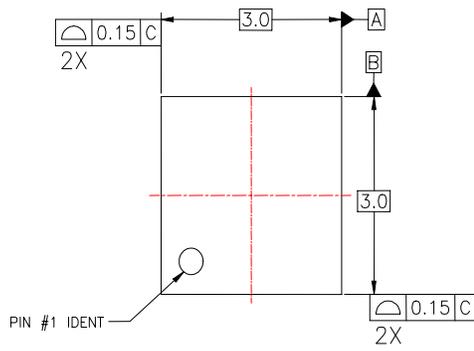


**Figure 10. Schottky Diode Reverse Current .**

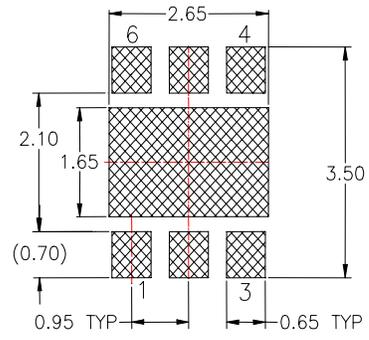


**Figure 11. Transient Thermal Response Curve.**

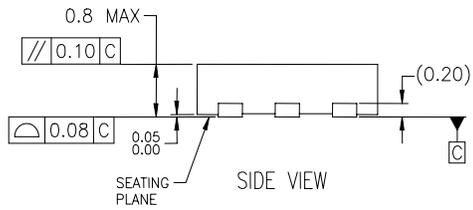
Thermal characterization performed using the conditions described in Note 1b.  
Transient thermal response will change depending on the circuit board design.



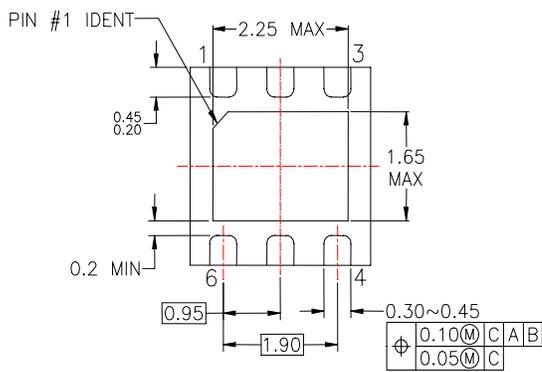
TOP VIEW



RECOMMENDED LAND PATTERN



SIDE VIEW



BOTTOM VIEW

NOTES :

- A. CONFORMS TO JEDEC REGISTRATION M0-229, VARIATION WEEA, DATE 11/2001.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M 1994

E Y14.5M, 1994

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